Attendance:

Mr. Bryan Kantack Agilent Technologies, Inc.

Mr. Jesse Jaramillo Amphenol
Mr. Jaremy Flake ATL Technology

Mr. Mickey Felton EMC
Mr. Ramez Rizk Emulex
Mr. Douglas Wagner FCI

Mr. Barry Olawsky
Mr. Harvey Newman
Hewlett Packard Co.
Infineon Technologies

Dr. Mark Seidel Intel Corp.
Mr. Michael Jenkins LSI Corp.
Mr. Gabriel Romero LSI Corp.

Mr. Jacky Chow Marvell Semiconductor, Inc. Mr. Kevin Witt Maxim Semiconductor

Mr. Galen Fromm Molex Inc.

Mr. Hock Seow NEC Electronics America, Inc

Mr. Yuming Tao PMC-Sierra Mr. Joseph Chen Samsung

Mr. Alvin Cox
Seagate Technology
Mr. Allen Kramer
Seagate Technology
Mr. Bruce Johnson
Seagate Technology

Mr. Bent Hessen-Schmidt Synthesys Research, Inc.

Mr. Kees Propstra Tektronix, Inc.

Mr. Mahbubul Bari Vitesse Semiconductor

Mr. Larry McMillan WDC Mr. Ramya Dissanayake WDC

26 in attendance

Agenda:

1. SAS-2 Calibration of Jitter Measurement Devices [Cox] http://www.t10.org/ftp/t10/document.07/07-443r1.pdf

No additional input yet.

2. Transmitter common mode measurements to validate the currently proposed chart. [Seagate to present; Intel, LSI looking at providing data]

Previous data posted at: http://www.t10.org/ftp/t10/document.07/07-445r0.pdf

These measurements need to be made through the mated SAS connector pair. Bruce Johnson indicated he would be able to do this.

- 3. Description of SSC profile allowed discontinuities. [Hernandez] No status update.
- 4. Should the cable specification be done by common mode requirements or fall under channel simulation? [Amphenol]

Promised to provide something for next week's call.

5. Define the delivered signal characteristics for physical receiver testing. Include 0.1UI sinusoidal jitter to do the equivalent of receiver tolerance testing. [Bari, Jenkins, Newman, Witt]

http://www.t10.org/ftp/t10/document.07/07-448r0.pdf http://www.t10.org/ftp/t10/document.07/07-448r0.zip

6. Refine/provide status on simulation technology. [Jenkins, Newman] Status update.

TWDP-based solutions may become available, but there is still a certain amount of uncertainty regarding this. The LSI DFEEYE is tailored for the FCAL and SAS applications. Kevin shared that he found certain errors in the input data that resulted in resulting eye distortion. New simulation results look encouraging. Kevin's presentation updates found on the links above.

http://www.t11.org/ftp/t11/pub/fc/pi-4/07-592v0.pdf

StatEye correlation between measured signal and simulation verification: http://www.t10.org/ftp/t10/document.07/07-455r0.pdf

Next conference call: October 25, 2007

Toll Free Dial in Number: (877)810-9442

International Access/Caller Paid Dial In Number: (636)651-3190

PARTICIPANT CODE: 3243413

Webex information:

https://seagate.webex.com/seagate

Topic: SAS-2 PHY WG

Date: Thursday

Time: 10:00 am, Central Daylight Time (GMT -05:00, Chicago)

Meeting number: 826 515 680 Meeting password: 6gbpsSAS